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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10091983	FILING DATE 03/06/2002	CLASS 134432	SUBCLASS 591	GAU 1746	2823 EXAMINER TOLED0 NEG. REF. EX. 1
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**APPLICANTS: Zhong Dong; Tan Yun; Ang Chew; Zheng Jia;

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**CONTINUING DATA VERIFIED:

** FOREIGN APPLICATIONS VERIFIED:

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed	<input type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO
35 USC 119 conditions met	<input type="checkbox"/> yes <input type="checkbox"/> no	CS01-067
Verified and Acknowledged Examiners's initials		
TITLE : Ultra-thin gate oxide through post decoupled plasma nitridation anneal		

U.S. DEPT. OF COMM./PAT. & TM-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
			Total Claims	Print Claim for O.G.
ISSUE FEE		Primary Examiner	DRAWING	
Amount Due	Date Paid		Sheets Drawn	Figs. Drawn
TERMINAL DISCLAIMER		PREPARED FOR ISSUE	Application Examiner	
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